

FDMS4D4N08C

MOSFET – POWERTRENCH[®], N-Channel Shielded Gate

80 V, 123 A, 4.3 mΩ

Description

This N-Channel MV MOSFET is produced using ON Semiconductor's advanced POWERTRENCH[®] process that incorporates Shielded Gate technology. This process has been optimized to minimise on-state resistance and yet maintain superior switching performance with best in class soft body diode.

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)}$ = 4.3 mΩ at $V_{GS} = 10\text{ V}$, $I_D = 44\text{ A}$
- Max $r_{DS(on)}$ = 10.4 mΩ at $V_{GS} = 6\text{ V}$, $I_D = 22\text{ A}$
- 50% Lower Q_{rr} than Other MOSFET Suppliers
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- RoHS Compliant

Typical Applications

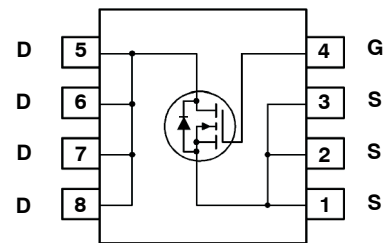
- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive
- Solar



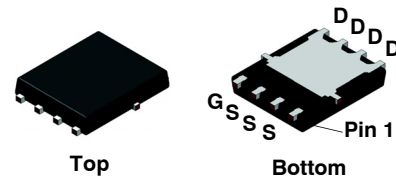
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ELECTRICAL CONNECTION

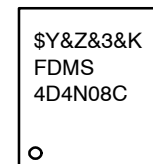


N-Channel MOSFET



Power 56
(PQFN8 5x6)
CASE 483AE

MARKING DIAGRAM



- | | |
|-------------|-------------------------|
| \$Y | = ON Semiconductor Logo |
| &Z | = Assembly Plant Code |
| &3 | = Numeric Date Code |
| &K | = Lot Code |
| FDMS4D4N08C | = Specific Device Code |

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

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MOSFET MAXIMUM RATINGS (T_A = 25°C, Unless otherwise specified)

Symbol	Parameter	Ratings	Unit
V _{DS}	Drain to Source Voltage	80	V
V _{GS}	Gate to Source Voltage	±20	V
I _D	Drain Current –Continuous T _C = 25°C (Note 5)	123	A
	–Continuous T _C = 100°C (Note 5)	78	
	–Continuous T _A = 25°C (Note 1a)	17	
	–Pulsed (Note 4)	498	
E _{AS}	Single Pulse Avalanche Energy (Note 3)	486	mJ
P _D	Power Dissipation T _C = 25°C	125	W
	Power Dissipation T _A = 25°C (Note 1a)	2.5	
T _J , T _{STG}	Operating and Storage Junction Temperature Range	–55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
R _{θJC}	Thermal Resistance, Junction to Case	1.0	°C/W
R _{θJA}	Thermal Resistance, Junction to Ambient (Note 1a)	50	

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Shipping [†]
FDMS4D4N08C	FDMS4D4N08C	PQFN8 5×6 (Pb-Free/Halogen Free)	3000 Units/ Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
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OFF CHARACTERISTICS

BV _{DSS}	Drain to Source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0 V	80			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25°C		63		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 64 V, V _{GS} = 0 V			1	μA
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA

ON CHARACTERISTICS (Note NO TAG)

V _{GS(th)}	Gate to Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 250 μA	2.0	3.0	4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 250 μA, referenced to 25°C		-8.2		mV/°C
r _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 44 A		3.7	4.3	mΩ
		V _{GS} = 6 V, I _D = 22 A		5.7	10.4	
		V _{GS} = 10 V, I _D = 44 A, T _J = 125°C		5.9	7.2	
g _{FS}	Forward Transconductance	V _{DS} = 5 V, I _D = 44 A		98		S

DYNAMIC CHARACTERISTICS

C _{ISS}	Input Capacitance	V _{DS} = 40 V, V _{GS} = 0 V, f = 1 MHz		2920	4090	pF
C _{OSS}	Output Capacitance			1045	1465	
C _{RSS}	Reverse Transfer Capacitance			35	50	
R _G	Gate Resistance		0.1	1.3	2.5	Ω

SWITCHING CHARACTERISTICS

t _{d(on)}	Turn – On Delay Time	V _{DD} = 40 V, I _D = 44 A, V _{GS} = 10 V, R _{GEN} = 6 Ω		17	31	ns
t _r	Rise Time			7	15	
t _{d(off)}	Turn – Off Delay Time			25	40	
t _f	Fall Time			5	10	
Q _g	Total Gate Charge	V _{GS} = 0 V to 10 V	V _{DD} = 40 V, I _D = 44 A	40	56	nC
Q _g	Total Gate Charge	V _{GS} = 0 V to 6 V		25	35	
Q _{gs}	Gate to Source Charge			13		
Q _{gd}	Gate to Drain "Miller" Charge			8		
Q _{OSS}	Output Charge	V _{DD} = 40 V, V _{GS} = 0 V		60		nC
Q _{sync}	Output Charge	V _{DS} = 0 V, I _D = 44 A		35		

DRAIN-SOURCE DIODE CHARACTERISTICS

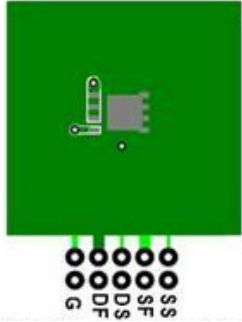
V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.1 A (Note 2)		0.7	1.2	V
		V _{GS} = 0 V, I _S = 44 A (Note 2)		0.8	1.3	
t _{rr}	Reverse Recovery Time	I _F = 22 A, di/dt = 300 A/μs		26	42	ns
Q _{rr}	Reverse Recovery Charge			44	71	nC
t _{rr}	Reverse Recovery Time	I _F = 22 A, di/dt = 1000 A/μs		20	32	ns
Q _{rr}	Reverse Recovery Charge			106	169	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

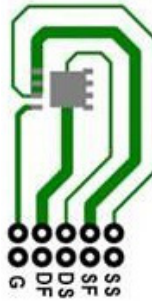
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NOTES:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 × 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



a) 50°C/W when mounted on a 1 in² pad of 2 oz copper.



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
3. E_{AS} of 486 mJ is based on starting $T_J = 25^\circ\text{C}$; $L = 3$ mH, $I_{AS} = 18$ A, $V_{DD} = 80$ V, $V_{GS} = 10$ V. 100% tested at $L = 0.1$ mH, $I_{AS} = 51$ A.
4. Pulsed I_D please refer to Fig. 11 SOA graph for more details.
5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

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TYPICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$ unless otherwise noted)

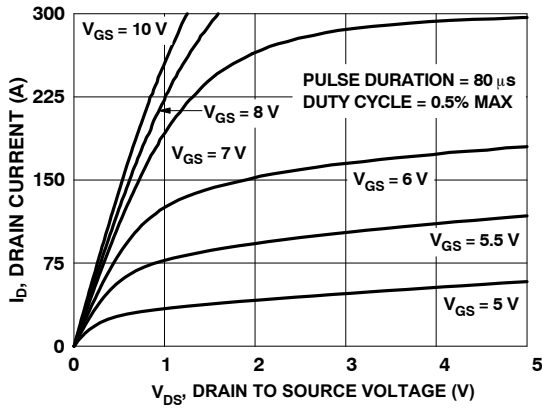


Figure 1. On Region Characteristics

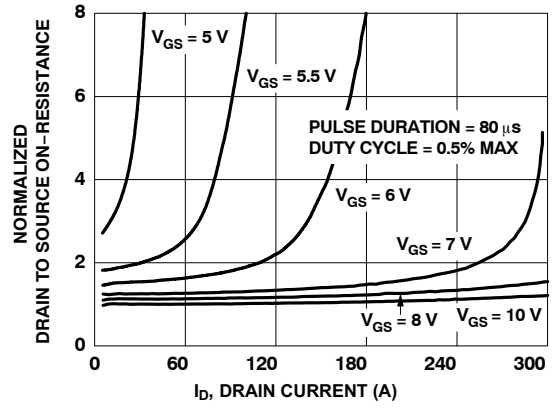


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

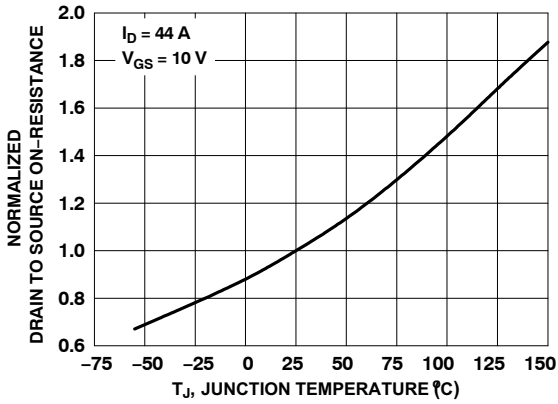


Figure 3. Normalized On Resistance vs. Junction Temperature

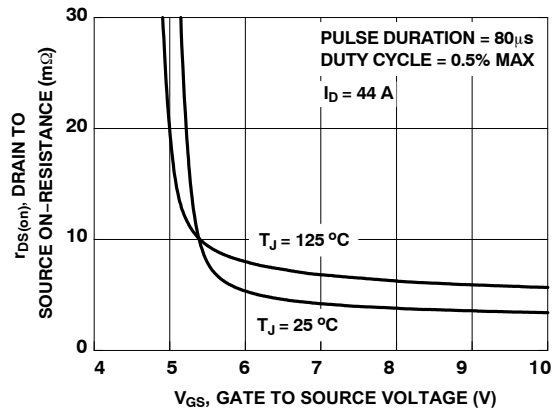


Figure 4. On-Resistance vs. Gate to Source Voltage

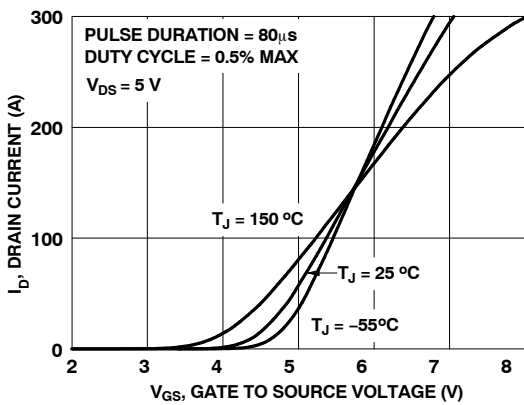


Figure 5. Transfer Characteristics

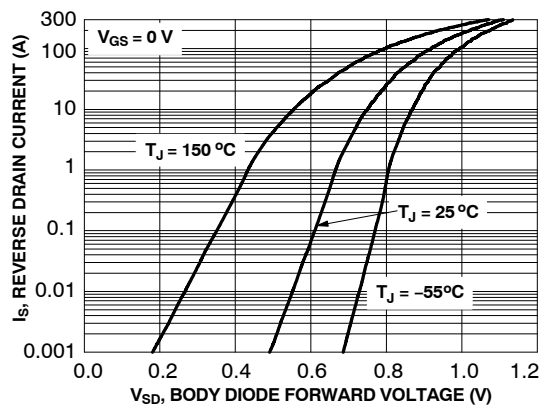


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

TYPICAL CHARACTERISTICS (continued)

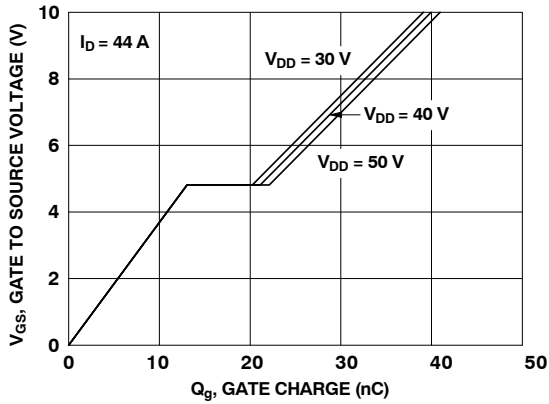


Figure 7. Gate Charge Characteristics

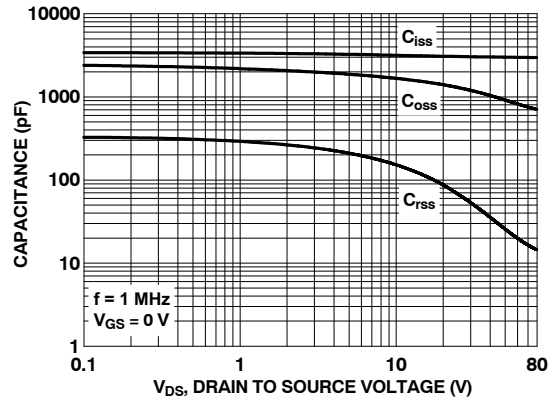


Figure 8. Capacitance vs. Drain to Source Voltage

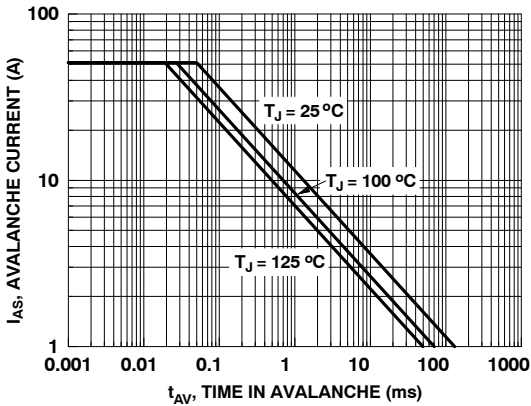


Figure 9. Unclamped Inductive Switching Capability

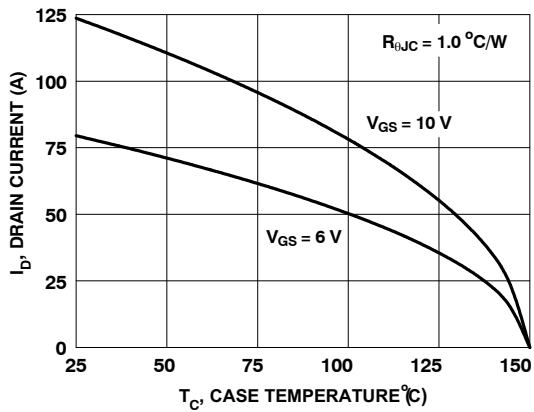


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

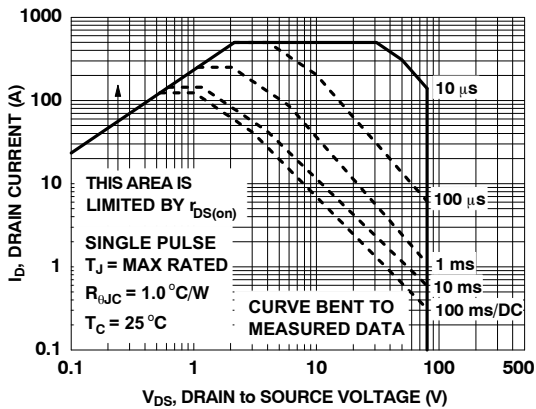


Figure 11. Forward Bias Safe Operating Area

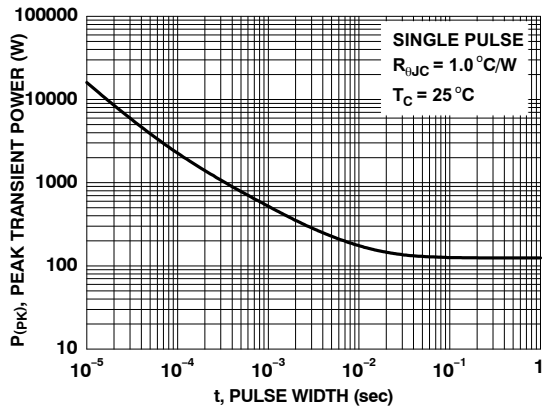


Figure 12. Single Pulse Maximum Power Dissipation

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TYPICAL CHARACTERISTICS (continued)

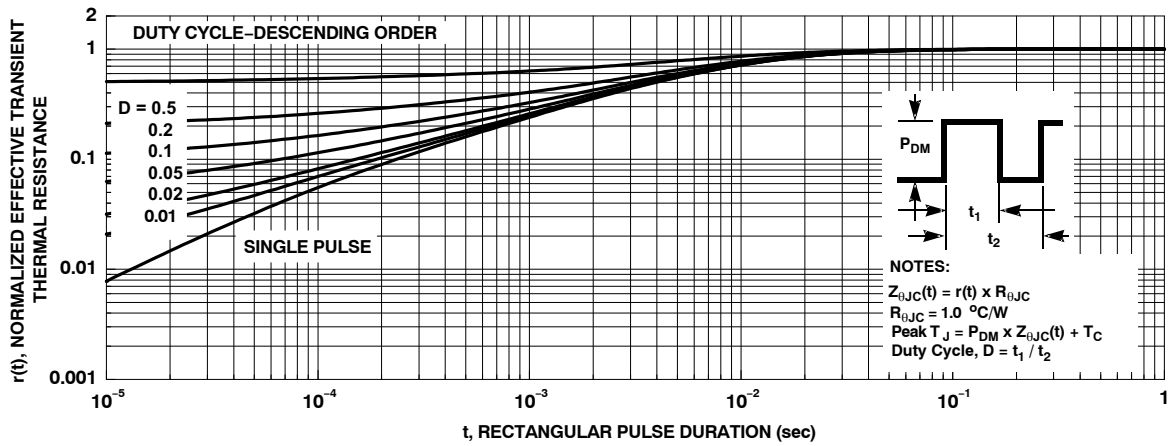


Figure 13. Junction-to-Case Transient Thermal Response Curve

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MECHANICAL CASE OUTLINE

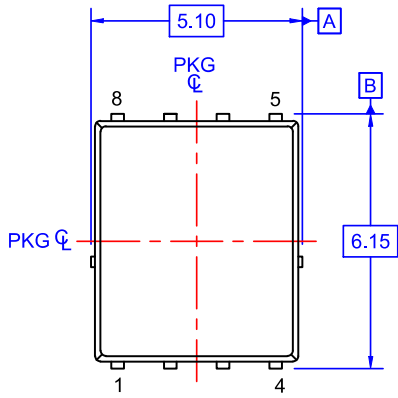
PACKAGE DIMENSIONS

ON Semiconductor®

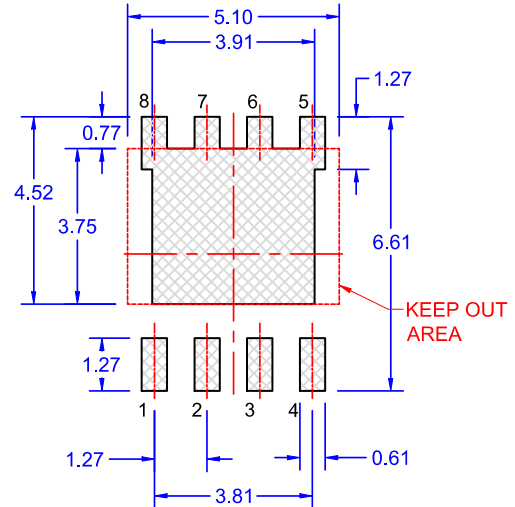
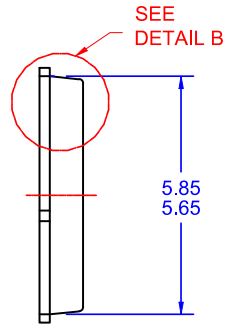


PQFN8 5X6, 1.27P
CASE 483AE
ISSUE A

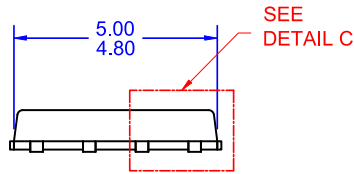
DATE 27 SEP 2017



TOP VIEW

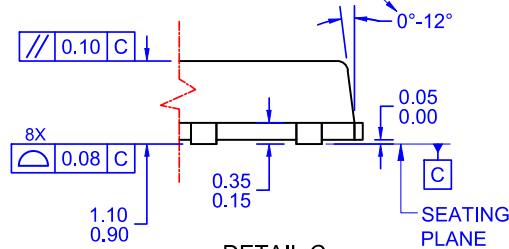


LAND PATTERN RECOMMENDATION

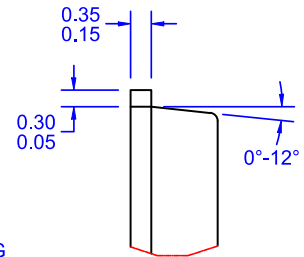


SIDE VIEW

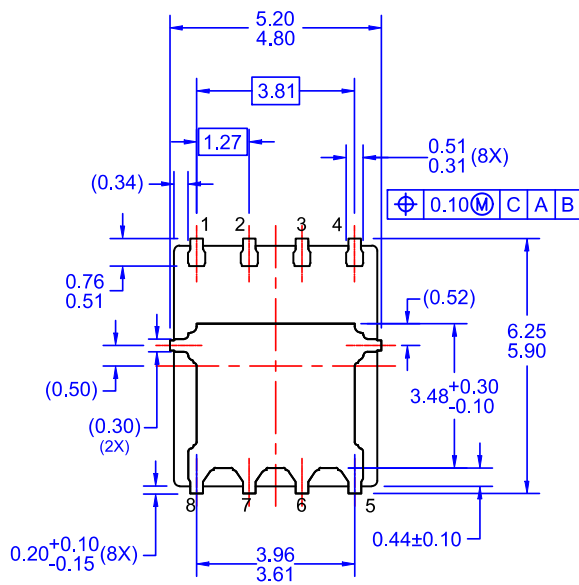
OPTIONAL DRAFT ANGLE MAY APPEAR ON FOUR SIDES OF THE PACKAGE



DETAIL C
 SCALE: 2:1




DETAIL B
 SCALE: 2:1



NOTES: UNLESS OTHERWISE SPECIFIED

- A. PACKAGE STANDARD REFERENCE: JEDEC MO-240, ISSUE A, VAR. AA.
- B. DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
- C. ALL DIMENSIONS ARE IN MILLIMETERS.
- D. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2009.
- E. IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.

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